

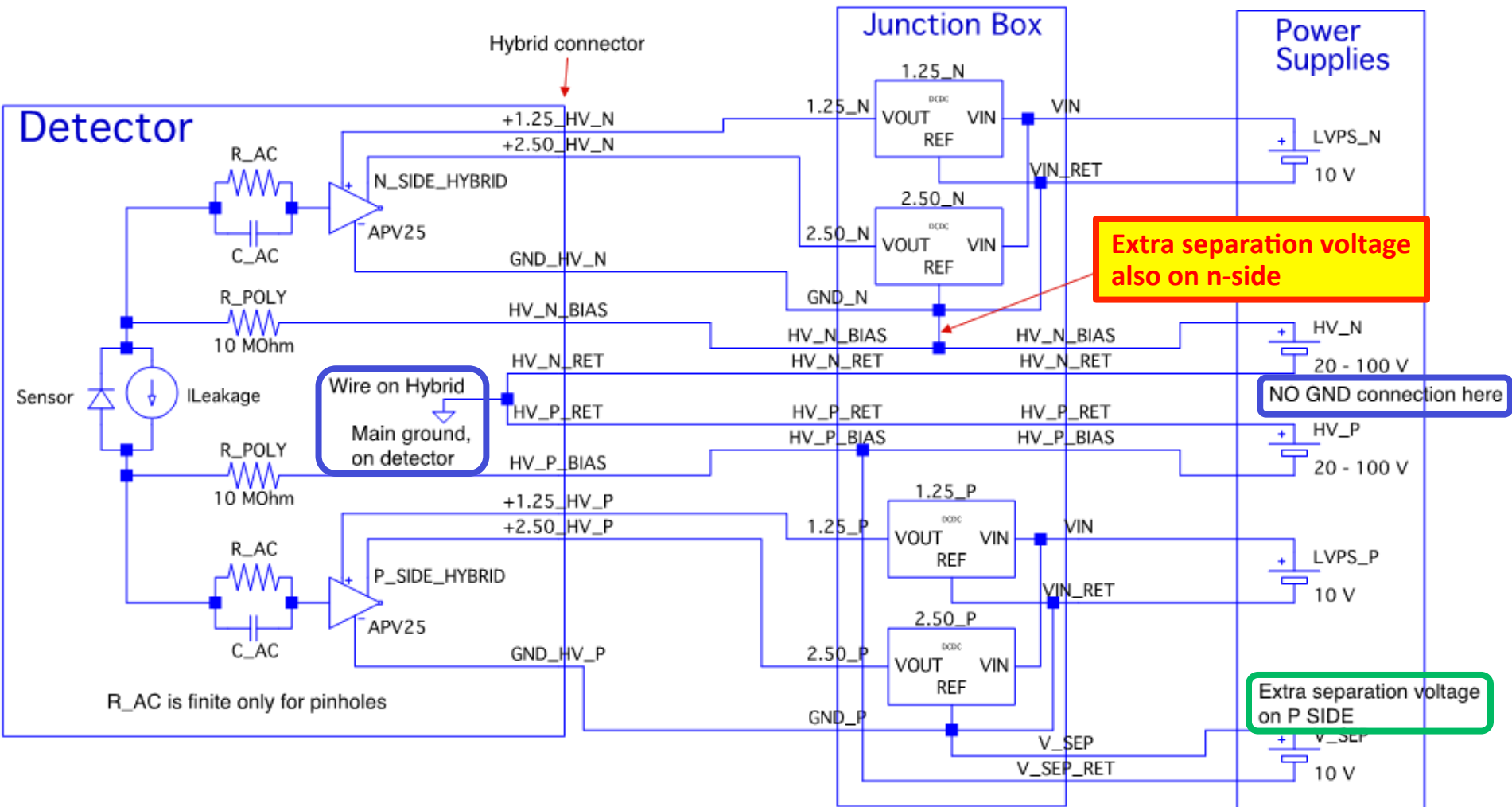
Pinholes and their effects of APV25 chips

- Pinholes
 - sensor strips are capacitively coupled to APV25
 - The capacitors, integrated on the sensor strips, can occasionally have a short circuit → pinhole.
- Pinhole can give DC current into/out from APV, which can:
 1. permanently disable the whole APV chip on p-side
 - due to APV INVERTER, used to change signal polarity and increase the dynamic range only on p-side (APV dynamic range +7MIPs /-2.5MIPs)
 - problem only arises on p-side (INVERTER) if current flow INTO APV:
 - APV input sits at +0.75V w.r.t APV_GND=HV_Bias
 - p side strips, collect holes, sit at HV_Bias+Ileak*Rbias → can inject current INTO APV
 - problem only if Ileak is big (rad damaged sensors) or/and several pinholes are connected to the same chip (details in backup slides)
 2. disable the single APV channel where pinhole is connected.
 - same effect on p and n side
- In CMS (single side sensor, p-side strips) all pinholes were then NOT connected to the APV chip to avoid problem 1

What we do in Belle2-SVD for pinholes

- In Belle2-SVD we proposed a new strategy for the pinholes!
- Saturation effect of the whole p-side chip can be avoided applying an extra voltage (V_{sep}) on APV_GND w.r.t HV_Bias
 - can rise V_{sep} to positive voltage so the current flows out of the APV chip, to sensor strip, and saturation cannot happen.
 - Extra voltage used already in BaBar to inhibit issues due to pinholes/p-stop short
- Advantages: disconnecting all the pinholes (as in CMS) can be difficult & new pinholes can develop later (radiation accidents!)
- This scheme (next slide) was proposed originally only to p side, since chip saturation cannot happen on n-side
 - CAEN boards for p side foreseen
- Recent studies on APVDAQ teststand (with real SVD modules) proved V_{sep} is effective:
 1. to avoid whole chip saturation on p side (expected)
 2. to cure single pinholes on p and n side (new)
 3. to recover single noisy strips: field plate effect of AC metal connected to the V_{sep} voltage via APV input (new)
- CAEN board for n side are needed

New Powering Scheme

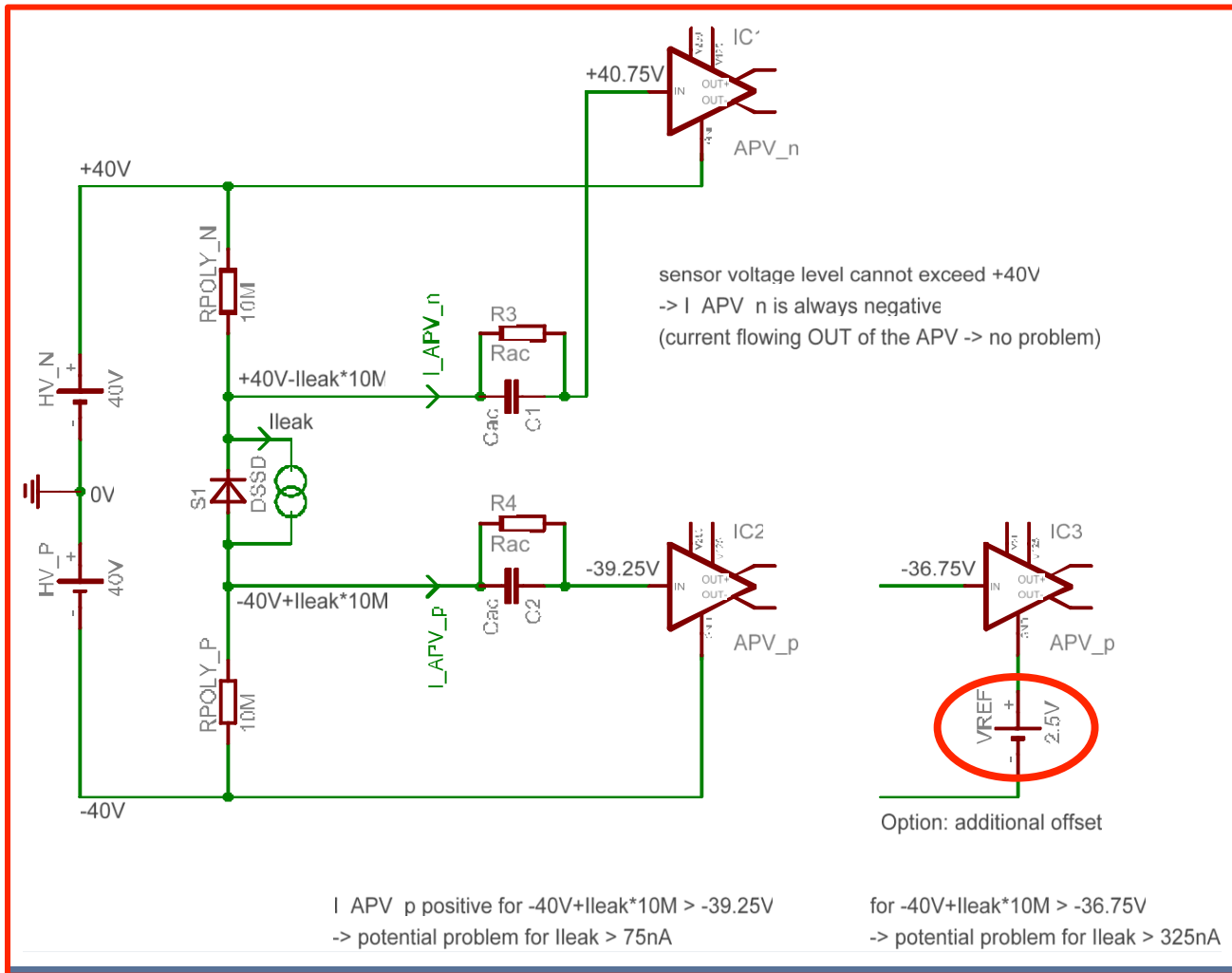


Vsep-extravoltage advantages

Recent studies on teststand with real SVD modules proved Vsep effects and various advantages on p and n side

1. Saturation effect on p side, on chips with several pinholes connected, demonstrated and cured with Vsep
 - Whole chip saturation starts with $V_{sep} < -3V$
 - All chans including pinholes, work normally $-2.5V < V_{sep} < -0.5V$
 - Pinholes stop working with $V_{sep} > -0.5V$ the other chans ok
2. Vsep can cure single connected pinholes on p & n side
 - with Vsep set to equalize the strip voltage and the input of the APV (+0.75V) no significant DC current is flowing in the pinhole and APV channel can work normally: $V_{sep} = -0.75V$ cure pinhole, for very low I_{leak}
3. Applying Vsep, via the APV input, on AC metal strips (no pinholes/AC capacitor OK) can be beneficial for noisy strips:
 - AC metal acts as a field plate above the n+ strip implant
 - With the right polarity/value can reduce strip leakage current coming from defects localized at the Si/SiO₂ surface
 - Noise reduction on defective strips observed/effect still under study

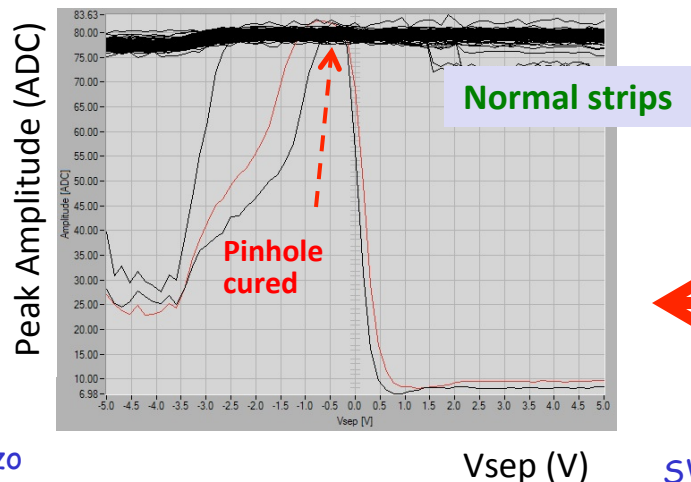
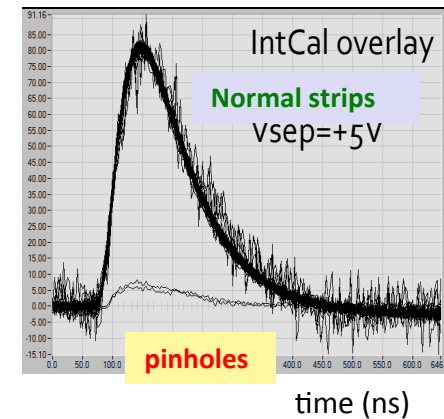
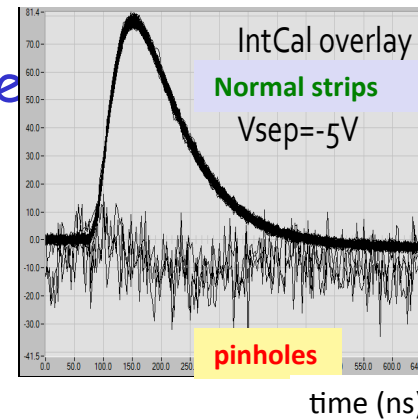
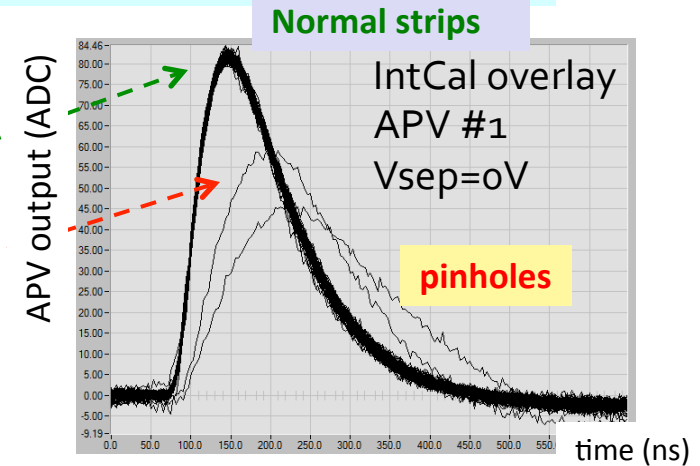
Pinholes studied on APVDAQ teststand



- **p-side only:** large current flow INTO APV, (several pinholes) is a problem for the whole chip
- **p & n side:** small current (single pinhole) disable a single APV channel
- **Remedy:** offset voltage between HV bias and APV_GND
- Some noisy channels (not pinholes) can be recovered with Vsep acting on AC metal as field plate

APV response to internal calibration

- Signal (MIP equivalent) injected from internal APV calibration circuit
- **Peak amplitude:**
 - 85 ADC for normal strips
 - smaller for pinholes connected
- Peak amplitude on pinholes reacts to Vsep extra voltage, as expected
- Vsep negative, -0.75V can cure single pinholes
 - equalize strip voltage and APV input

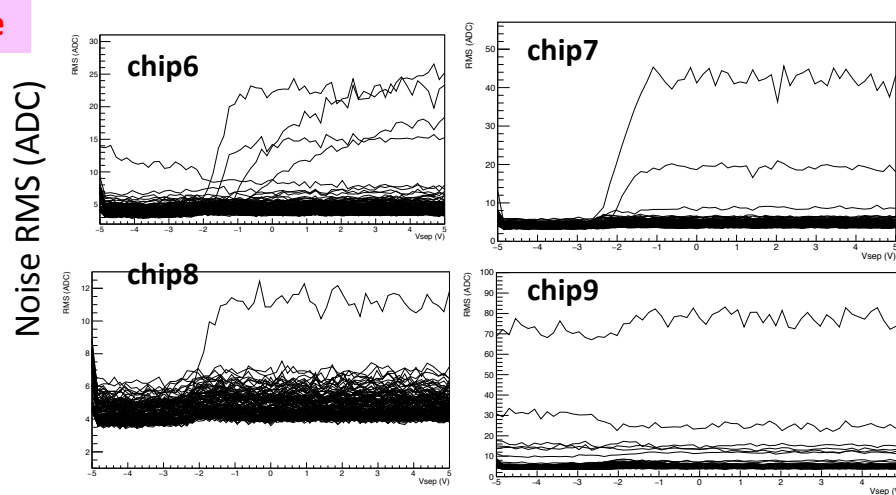
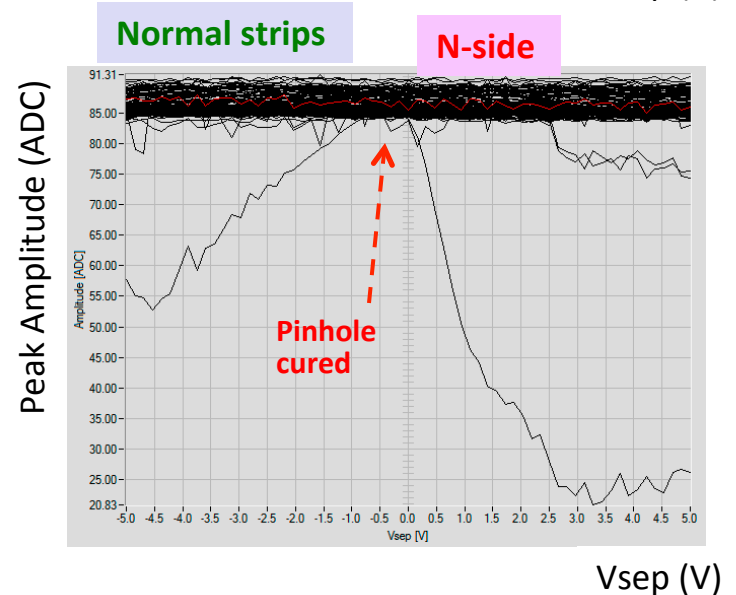
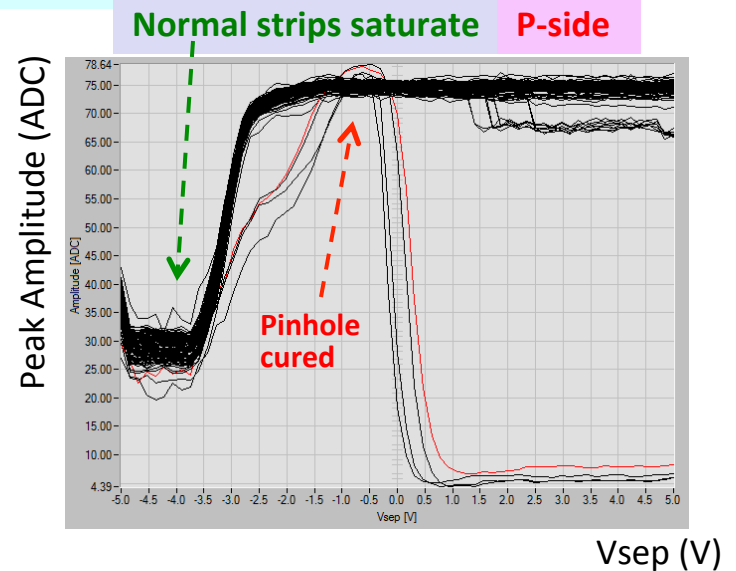


Only peak amplitude
sampled & fine Vsep scan
implemented on APVDAQ



Vsep scan results

1. Whole chip saturation induced artificially with $V_{sep} < -3V$ in chips with several pinholes connected
 2. Single pinholes on p and n side cured
 3. Some single strips noisy (not pinhole) can be cured : field plate effect of AC metal connected to the V_{sep} voltage via APV input (new effect under study)
- V_{sep} adds some degree of freedom on p and n side to compensate some defects

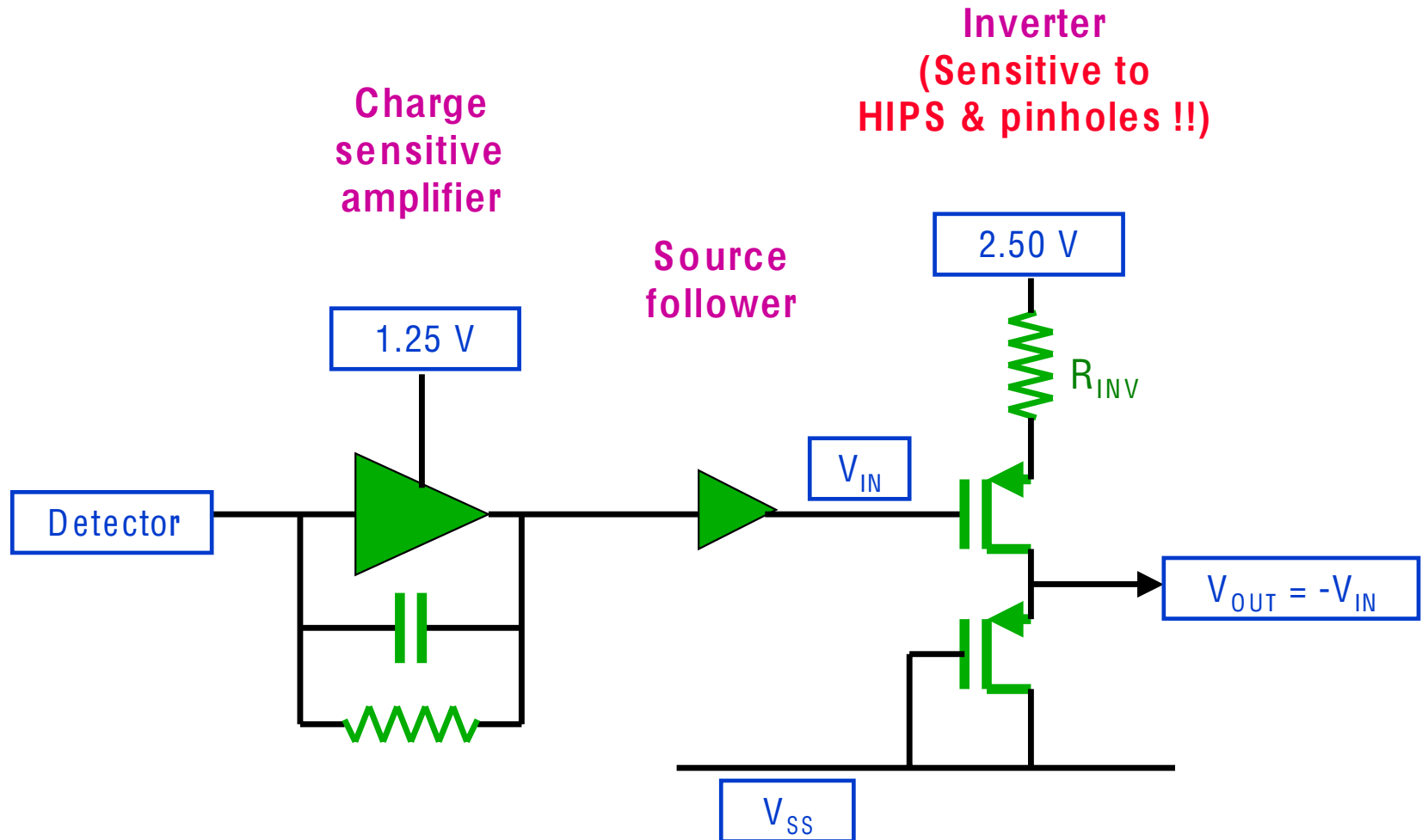


Backup



Introduction

Internal Workings of the APV





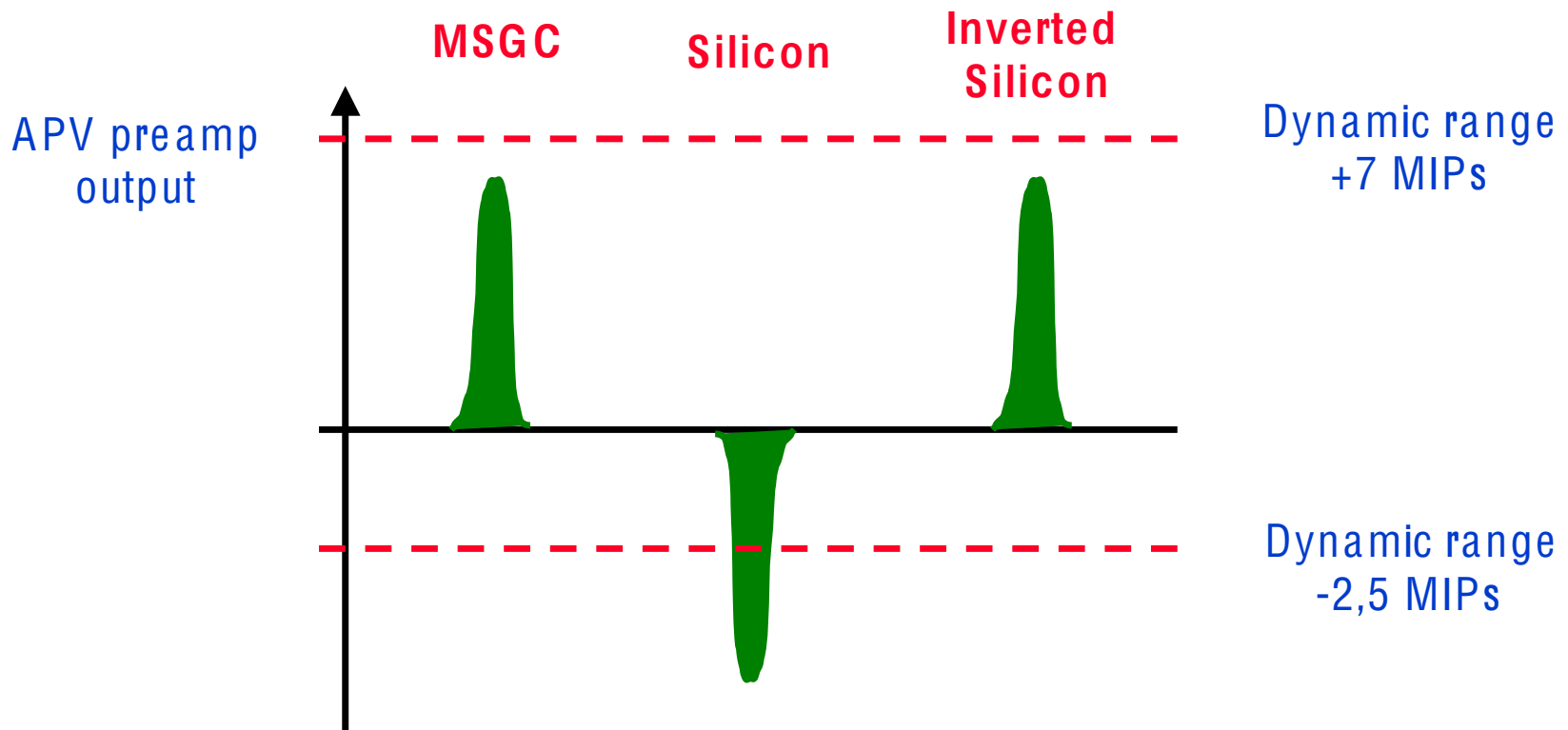
Introduction

Internal Workings of the APV



Why is the inverter there ?

- It increases APV dynamic range for silicon strip detector.





Introduction

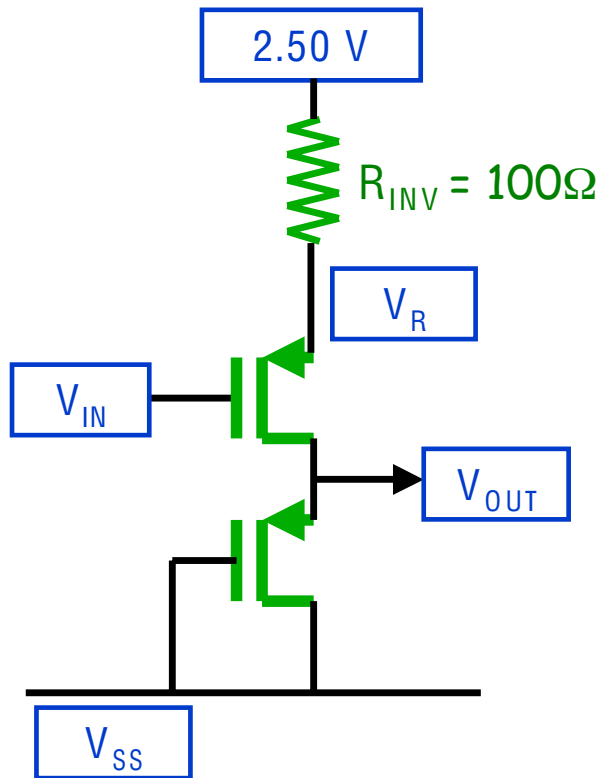
How HIPs & Pinholes affect the APV



❖ Big signal from silicon (holes) gives -ve pulse at V_{IN} :

➤ Inverter FET switches hard on, which steals current from 127 other inverters. (APV disabled until capacitor discharges.)

➤ N.B. If R_{INV} were reduced, total current available to inverters would increase.



❖ Leakage current via pinhole into APV :

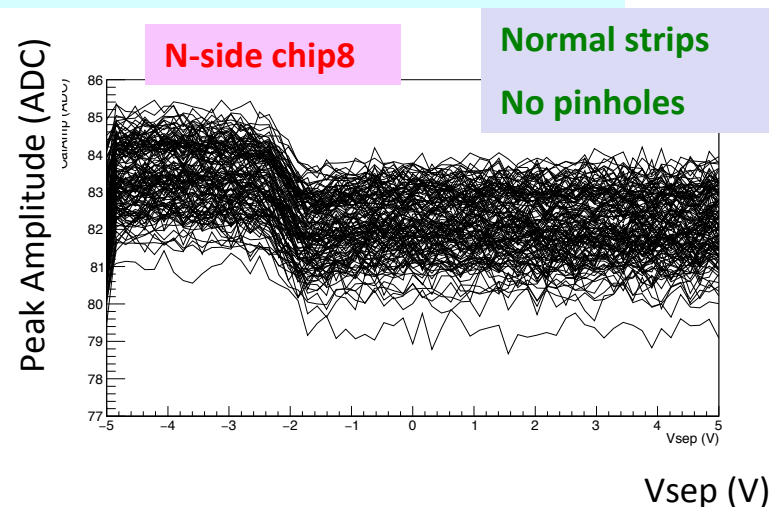
➤ Same again, but permanent.

❖ Leakage current via pinhole out of APV :

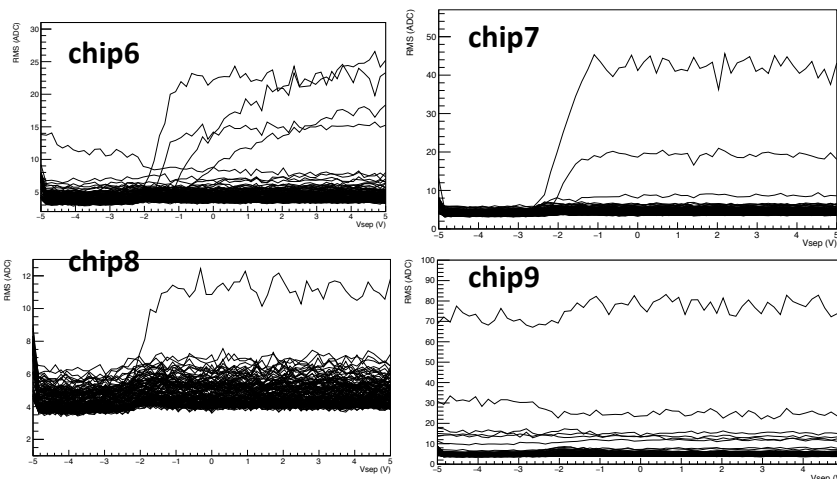
➤ Inverter FET switches hard off. Takes no current, so other 127 channels still work.

Vsep scan on n side HPK sensor

- Small (a few %) reduction of Calamp (and increase in caltmax) on all n side strip @ $V_{sep} > -2V$
- Some single strips become very noisy @ $V_{sep} > -2V \rightarrow V_{sep} < -2V$ can cure them!
- Other noisy strip not sensitive to V_{sep}



RMS (ADC)



- Only seen on 1 HPK sensor
- Seen also on other sensor in HEPHY?

- Possible explanation for both effect:
 - field plate effect of AC metal connected to the V_{sep} voltage via APV input

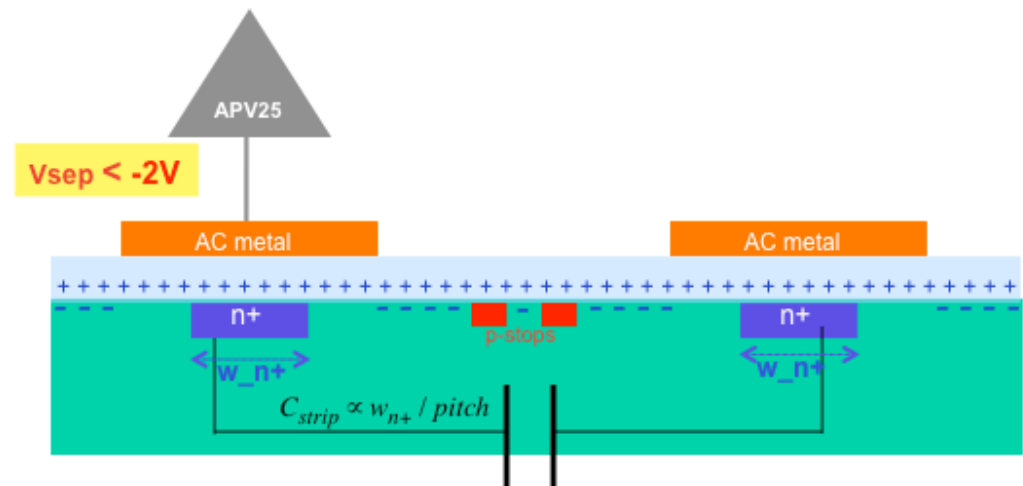
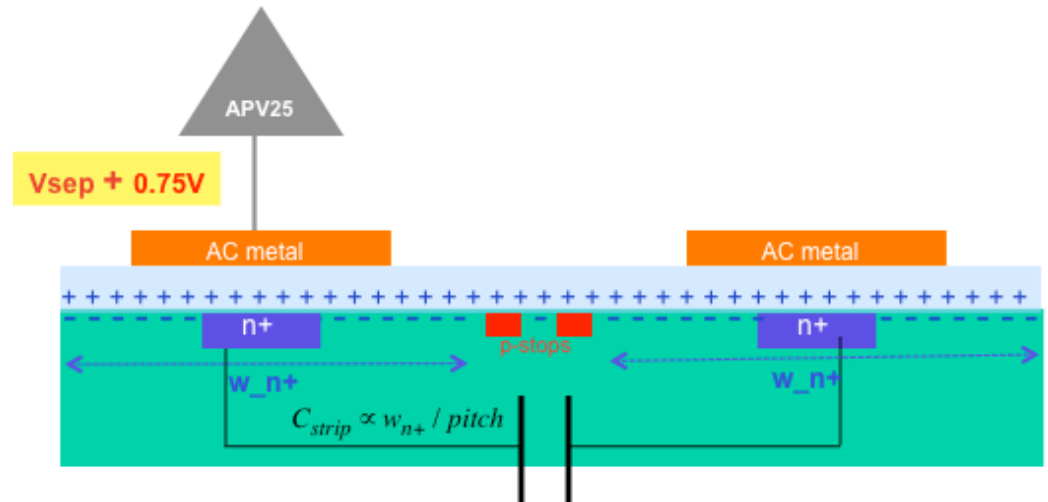
Vsep scan on n side HPK sensor

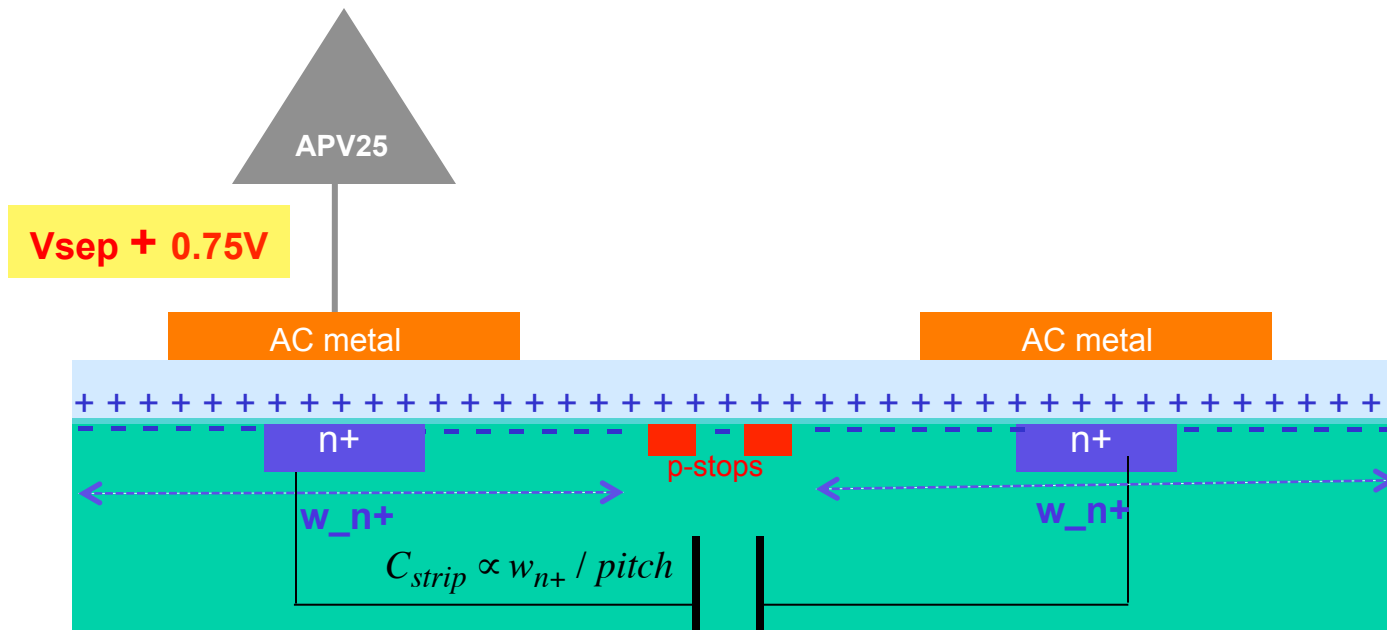
1. Small reduction of Calamp (and increase in caltmax) on all n side strip @ $V_{sep} > -2V$
 2. Some single strips become very noisy @ $V_{sep} > -2V$
- Possible explanation for both effects:
 - field plate effect of AC metal connected to the Vsep voltage via APV input
 - Negative voltage ($V_{sep} < -2V$) on AC n side metal reduces the extension of the electrons accumulation layer and reduces the effective width of n+ implant
 1. C interstrip, proportional to width /pitch, is reduced for all strips and consequently Calamp (increase) and Caltmax move (sensitive to the Capacitance connected to the APV input)
 2. When the extension of the n strip implant changes the localized defects at surface that can produce leakage current can/cannot contribute to the strip leakage current and noise increase/decrease.
 - Field effect on AC metal could be studied on sensors (n and p side) and, to be pragmatic, effects on modules noise vs Vsep should be studied.
 - We might find the best optimization for Vsep operation on n and p side to: cure pinholes, reduce the noisy strips

Vsep (V)

Vsep scan and field effect on AC metal

- With **Vsep negative** the AC metal acts as a field plate and reduces the accumulation layer extension close to the n+ strip implant → **effective implant width w_{n+} is reduced**
- 1. Interstrip capacitance, proportional to width/pitch, is reduced → Peak amplitude increases slightly
- The Electric field close to the n+ strip is modified by the field plate effect
 - Some defects very close to the surface Si-SiO₂ (that can be the origin of high leakage current) can stop to contribute to the strip leakage current??
 - The peak electric field can be lowered, thus reducing the impact ionization in spots where localized defects are responsible for high field values.





- When **Vsep is negative enough**, the AC metal field plate depletes the accumulation layer close to the n+ strip implant → **effective n-strip width w_n+ is reduced**
- **Interstrip capacitance is reduced by the addition of two non-conducting gaps** (but the metal is still wide, so the reduction is not expected to be dramatic). The effect will be tested on bare sensors.

